

	U	Pub	Document ID	Issue Date	Pages	Title	Current OR	Current XRef	Retrieval Class	Inventor	B	C	P	S	A	U	U
1		P	US 4767211 A	19880830	18	Apparatus for and method of measuring boundary surface	356/624	356/446; 356/609	356/624	Munakata, Chusuke et al.	P	P	P	P	P	P	US
2		P	US 20030215725 A1	20031120	20	Method for determining depth of focus	430/30	355/55; 355/77	356/624	Watanabe, Akira	P	P	P	P	P	P	US
3		P	US 20030038950 A1	20030227	9	Apparatus for handling liquids and a process for operating the device	356/624		356/624	Spolaczyk, Reiner	P	P	P	P	P	P	US
4		P	US 6819437 B2	20041116	9	Apparatus for handling liquids and a process for operating the device	356/624	250/577; 356/128	356/624	Spolaczyk, Reiner	P	P	P	P	P	P	US
5		P	US 6819436 B2	20041116	42	Image capturing apparatus and distance measuring method	356/614	356/3.1; 356/4.07	356/624	Ono, Shuji	P	P	P	P	P	P	US
6		P	US 6763140 B1	20040713	19	Method and apparatus for focusing a micro-imaging system onto a tiled or	382/255	250/201.6; 356/624	356/624	Skol, David F.	P	P	P	P	P	P	US
7		P	US 6633390 B2	20031014	46	Focus measurement in projection exposure apparatus	356/620	250/201.2; 250/201.4	356/624	Shiode, Yoshinori et al.	P	P	P	P	P	P	US
8		P	US 6628390 B1	20030930	20	Wafer alignment sensor using a phase-shifted microlens array	356/400	356/401; 356/485	356/624	Johnson, Kenneth C.	P	P	P	P	P	P	US
9		P	US 6538751 B2	20030325	48	Image capturing apparatus and distance measuring method	356/614	356/3.1; 356/602	356/624	Ono, Shuji	P	P	P	P	P	P	US